

# JEIDA Ver. 4 UNPROGRAMMED ONE TIME PROGRAMMABLE ROM

## VARIATION

Part Number	Memory Size	Description
BWB065SD*0	64K Bytes	32K × 16 bits JEIDA Ver.4 CMOS OTP ROM CARD
BWB129SD*0	128K Bytes	64K × 16 bits JEIDA Ver.4 CMOS OTP ROM CARD
BWB257SD*0	256K Bytes	128K × 16 bits JEIDA Ver.4 CMOS OTP ROM CARD
BWB513SD*0	512K Bytes	256K × 16 bits JEIDA Ver.4 CMOS OTP ROM CARD
BWB101SD*0	1M Bytes	512K × 16 bits JEIDA Ver.4 CMOS OTP ROM CARD (Under development)
BWB201SD*0	2M Bytes	1M × 16 bits JEIDA Ver.4 CMOS OTP ROM CARD (Under development)

Note: \* : Attribute memory type  
 X : 2K Bytes EEPROM (can be read/written)  
 Y : No attribute memory (output “FF”) (read only)

## OUTLINE OF FUNCTIONS AND FEATURES

- (1) This memory card conforms to JEIDA Ver. 4.
- (2) Size of the card
  - Width : 54.0 mm
  - Length : 85.6 mm
  - Thickness : 3.3 mm
- (3) Includes exclusive IC's for the control of I/O and power functions.
- (4) Support 2 type attribute memory
  - 4-1) With 2K Bytes EEPROM which can be read/written.
  - 4-2) Without attribute memory which can be read only. (output “FF”)
- (5) This card is only used for customer's development.
- (6) Card Type : 68 pin Two-piece Type

## MAXIMUM RATING

Symbol	Description	Note	Min	Max	Unit
VCC	Supply voltage		-0.5	7.0	V
VIN	Input signal voltage	1	-0.5	VCC +0.5	V
VOUT	Output signal voltage	1	-0.5	VCC	V
TOPR	Operating temperature		0	60	°C
TSTR	Storage temperature		-20	60	°C
HUM	Humidity	2	10	90	%
PD	Power dissipation			2.0	W
VPP	Program supply voltage		-0.5	14.0	V

- Notes:
1. Under 7.0 V
  2. No dew condition

## CAPACITANCE

(Ta = 25°C, VIN / VOUT = 0 V, f = 1 MHz)

Symbol	Description	Min	Typ	Max	Unit
C1	Input capacitance		10	14	pF
C2	Input/output capacitance		10	14	pF

Note: The above figures are for reference only

**RECOMMENDED DC OPERATING CONDITIONS**

Symbol	Description	Min	Typ	Max	Unit
VCC	Supply voltage at read	4.75	5.0	5.25	V
VPP	Supply at read	4.75	5.0	5.25	V
VCC	Supply voltage at write	6.0	6.25	6.5	V
VPP	Supply at write	12.5	12.75	13.0	V
VIH	High level input voltage	3.5	—	VCC +0.3	V
VIL	Low level input voltage	-0.3	—	1.0	V

**DC ELECTRICAL CHARACTERISTICS**

(VCC = 5 V, Ta = 25°C)

Symbol	Description	Note	Condition	Min	Typ	Max	Unit
ILI	Low level input current	1, 3	VIN = 0 V	-10	—	10	μA
		2		-53	—	-48	μA
IHI	High level input current	1, 2	VIN = 5 V	-10	—	100	μA
		3		10	—	50	μA
VOH	High level output voltage	3	IOH = -2.0 mA	VCC-0.4	—	—	V
VOL	Low level output voltage	3	IOL = 6.0 mA	—	—	VSS +0.4	V

- Notes : 1. A0 to A20  
 2.  $\overline{CE1}$ ,  $\overline{CE2}$ ,  $\overline{WE}$ ,  $\overline{OE}$ ,  $\overline{REG}$   
 Pull-up to VCC through 100K ohm  
 3. D0 to D15  
 Pull-down to GND through 100K ohm

## CURRENT CONSUMPTION

( $T_a = 25^\circ\text{C}$ ,  $V_{CC} = 5\text{ V} \pm 5\%$ )

Symbol	Description	Condition	Min	Typ	Max	Unit	
ISTBY	Standby current	$\overline{\text{CE}} = \overline{\text{WE}} = \overline{\text{OE}} = \overline{\text{REG}} =$ $V_{CC} - 0.2\text{ V}$ Other = $V_{IL}/V_{IH}$	—	1.0	1.5	mA	
IACT1	Active current (Read)	$\overline{\text{CE}} = V_{IL}$ , $I_{OUT} = 0\text{ mA}$ , Other = $V_{IL}/V_{IH}$	$f = 1\text{MHz}$	—	20	40	mA
			$f = \text{Max}$	—	—	70	mA
IACT2	Active current (Program)	Programming ( $I_{CC}$ )	—	—	60	mA	
I <sub>PP1</sub>	V <sub>PP</sub> current (Read)	$V_{PP} = V_{CC} \pm 0.25\text{ V}$	-20	—	20	$\mu\text{A}$	
I <sub>PP2</sub>	V <sub>PP</sub> current (Program)	$V_{PP} = 13\text{ V}$	—	—	100	mA	

## OPERATING MODES (READ) OF COMMON MEMORY

Mode	REG	A <sub>0</sub>	$\overline{\text{CE}}1$	$\overline{\text{CE}}2$	$\overline{\text{OE}}$	WE	D <sub>0</sub> to D <sub>7</sub>	D <sub>8</sub> to D <sub>15</sub>
Standby	*	*	$V_{IH}$	$V_{IH}$	*	*	HZ	HZ
Even data read	$V_{IH}$	$V_{IL}$	$V_{IL}$	$V_{IH}$	$V_{IL}$	$V_{IH}$	Output	HZ
ODD data read 1	$V_{IH}$	$V_{IH}$	$V_{IL}$	$V_{IH}$	$V_{IL}$	$V_{IH}$	Output	HZ
ODD data read 2	$V_{IH}$	*	$V_{IH}$	$V_{IL}$	$V_{IL}$	$V_{IH}$	HZ	Output
Word read	$V_{IH}$	*	$V_{IL}$	$V_{IL}$	$V_{IL}$	$V_{IH}$	Output	Output

Notes: HZ = High impedance  
(Pull-down to GND through 100K ohm)

\* = Input is  $V_{IH}$  or  $V_{IL}$

V<sub>PP</sub> =  $V_{CC} \pm 0.25\text{ V}$

**OPERATING MODES OF ATTRIBUTE MEMORY**

Mode	REG	A0	A1 to A11	CE1	CE2	OE	WE	D0 to D7	D8 to D1
Data read	VIL VIL	VIL VIH	* *	VIL VIL	VIH VIH	VIL VIL	VIH VIH	Output HZ	HZ HZ
Word data read	VIL	*	*	VIL	VIL	VIL	VIH	Output	HZ
Data write	VIL VIL	VIL VIH	* *	VIL VIL	VIH VIH	VIH VIH	VIL VIL	Input don't care	don't care don't care
Word data write	VIL	*	*	VIL	VIL	VIH	VIL	Input	don't care

Notes: HZ = High impedance  
(Pull-down to GND through 100K ohm)  
\* = Input is VIH or VIL

**OPERATING MODES (PROGRAM) OF COMMON MEMORY**  
(VPP = 12.75 V ±0.25V, VCC = 6.25 V ±0.25 V)

Mode	REG	A0	CE1	CE2	OE	PGM	D0 to D7	D8 to D15	VPP1	VPP2
Standby	*	*	VIH	VIH	*	*	HZ	HZ	VCC	VCC
Even data program	VIH	VIL	VIL	VIH	VIH	VIL	Input	don't care	VPP	VCC
Odd data program 1	VIH	VIH	VIL	VIH	VIH	VIL	Input	don't care	VCC	VPP
Even data program 2	VIH	*	VIH	VIL	VIH	VIL	don't care	Input	VCC	VPP
Word data program	VIH	*	VIL	VIL	VIH	VIL	Input	Input	VPP	VPP

**OPERATING MODES (PROGRAM) OF COMMON MEMORY**
**(VPP = 12.75 V ±0.25V, VCC = 6.25 V ±0.25 V)**

Mode	REG	A0	CE1	CE2	OE	PGM	D0 to D7	D8 to D15	VPP1	VPP2
Even data program Verify	V <sub>IH</sub>	V <sub>IL</sub>	V <sub>IL</sub>	V <sub>IH</sub>	V <sub>IL</sub>	V <sub>IH</sub>	Output	HZ	V <sub>PP</sub>	V <sub>CC</sub>
Odd data program Verify 1	V <sub>IH</sub>	V <sub>IH</sub>	V <sub>IL</sub>	V <sub>IH</sub>	V <sub>IL</sub>	V <sub>IH</sub>	Output	HZ	V <sub>CC</sub>	V <sub>PP</sub>
Odd data program Verify 2	V <sub>IH</sub>	*	V <sub>IH</sub>	V <sub>IL</sub>	V <sub>IL</sub>	V <sub>IH</sub>	HZ	Output	V <sub>CC</sub>	V <sub>PP</sub>
Word data program verify	V <sub>IH</sub>	*	V <sub>IL</sub>	V <sub>IL</sub>	V <sub>IL</sub>	V <sub>IH</sub>	Output	Output	V <sub>PP</sub>	V <sub>PP</sub>

Notes: \* = Input is V<sub>IH</sub> or V<sub>IL</sub>

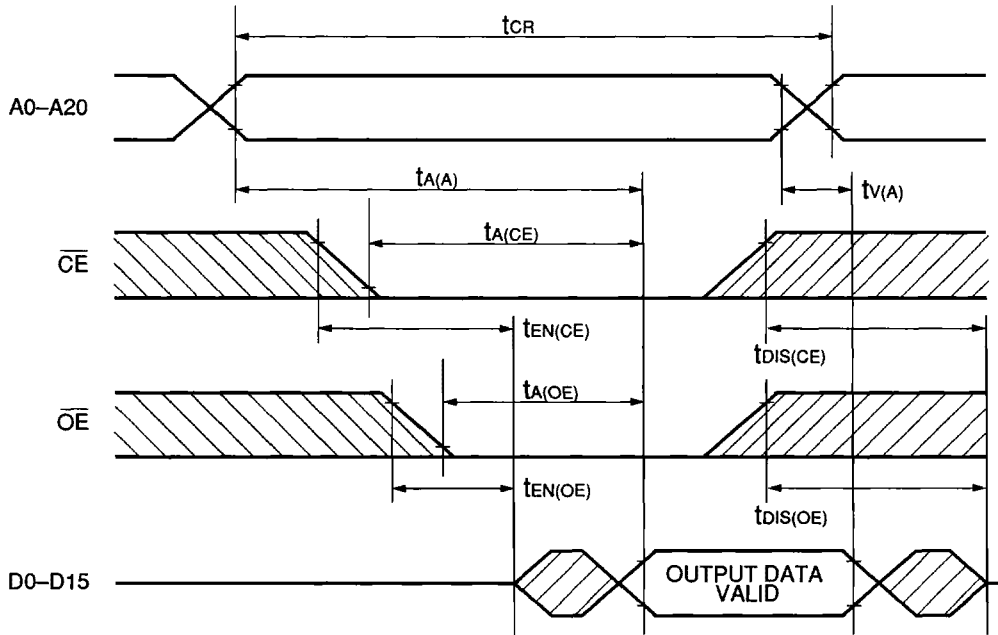
HZ = High impedance

(Pull-down to GND through 100K ohm)

**AC ELECTRICAL CHARACTERISTICS AT READ OF COMMON MEMORY**

Symbol	Parameter	Min	Max	Unit
t <sub>CR</sub>	Read cycle time	250	—	ns
t <sub>A</sub> (A)	Address access time	—	250	ns
t <sub>A</sub> (CE)	Card enable access time	—	250	ns
t <sub>A</sub> (OE)	Output enable access time	—	125	ns
t <sub>DIS</sub> (CE)	Output disable time from card enable	—	100	ns
t <sub>DIS</sub> (OE)	Output disable time from output enable	—	100	ns
t <sub>EN</sub> (CE)	Output enable time from card enable	5	—	ns
t <sub>EN</sub> (OE)	Output enable time from output enable	5	—	ns
t <sub>V</sub> (A)	Valid data hold time from address invalid	0	—	ns

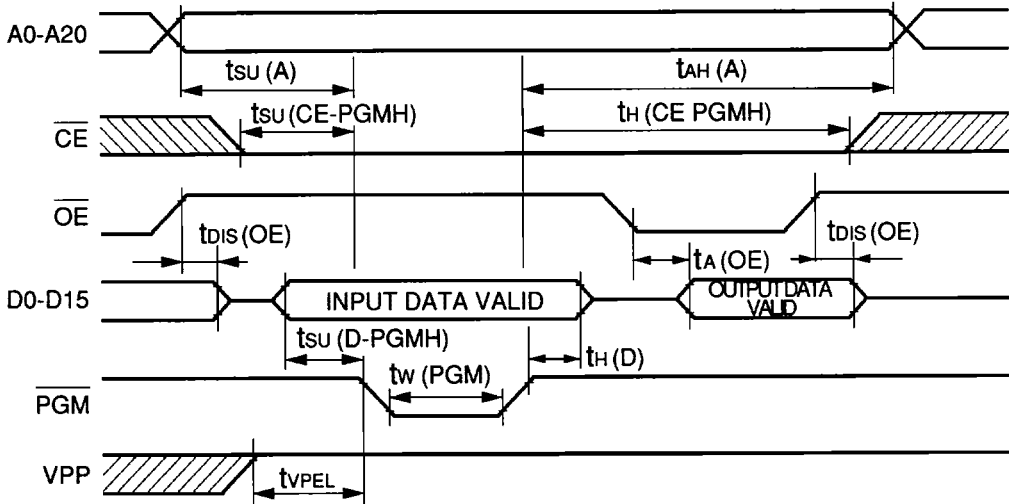
**READ TIMING OF COMMON MEMORY**



**AC ELECTRICAL CHARACTERISTICS AT PROGRAM OF COMMON MEMORY**

Symbol	Parameter	Min	Max	Unit
$t_{SU(A)}$	Address setup time	2	—	us
$t_{AH(A)}$	Address hold time	2	—	us
$t_{SU(D-PGMH)}$	Data setup time	2	—	us
$t_{H(D)}$	Data hold time	2	—	us
$t_{SU(CE-PGMH)}$	Card enable setup time	2	—	us
$t_{H(CE-PGMH)}$	Card enable hold time	2	—	us
$t_w(PGM)$	Write pulse width	95	105	us
$t_A(OE)$	Output enable access time	—	150	ns
$t_{DIS(OE)}$	Output disable time from output enable	—	100	ns
$t_{VPEL}$	VPP setup time	2	—	us

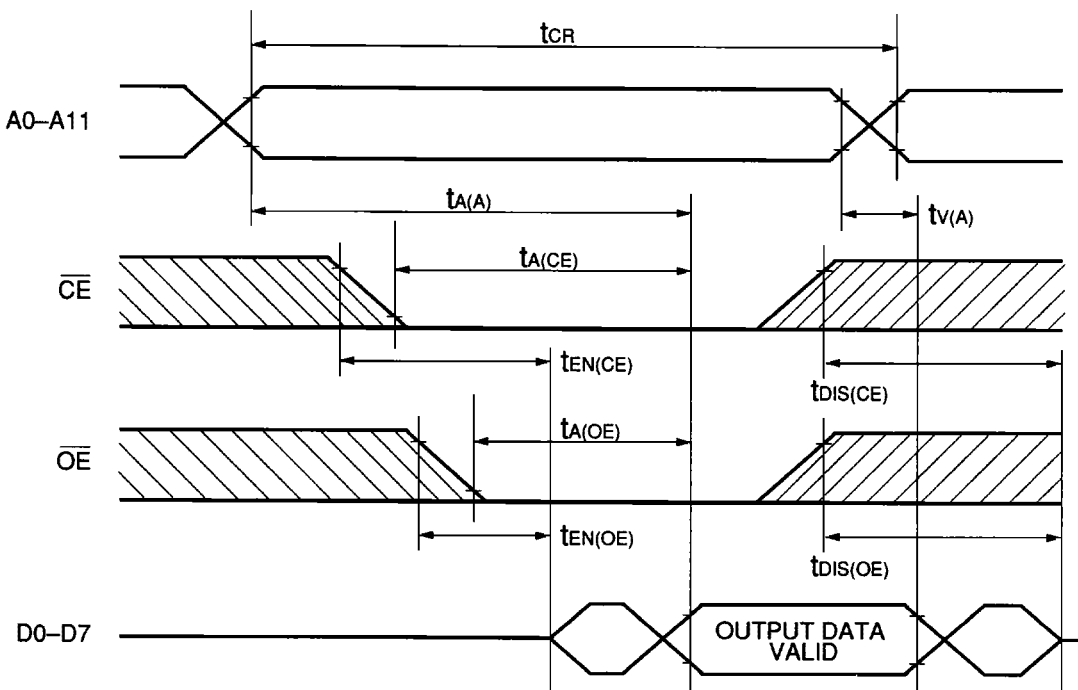
PROGRAM TIMING OF COMMON MEMORY



**AC ELECTRICAL CHARACTERISTICS AT READ OF ATTRIBUTE MEMORY**

Symbol	Parameter	Min	Max	Unit
$t_{CR}$	Read cycle time	300	—	ns
$t_A(A)$	Address access time	—	300	ns
$t_A(CE)$	Card enable access time	—	300	ns
$t_A(OE)$	Output enable access time	—	150	ns
$t_{DIS}(CE)$	Output disable time from card enable	—	100	ns
$t_{DIS}(OE)$	Output disable time from output enable	—	100	ns
$t_{EN}(CE)$	Output enable time from card enable	5	—	ns
$t_{EN}(OE)$	Output enable time from output enable	5	—	ns
$t_v(A)$	Valid data hold time from address invalid	0	—	ns

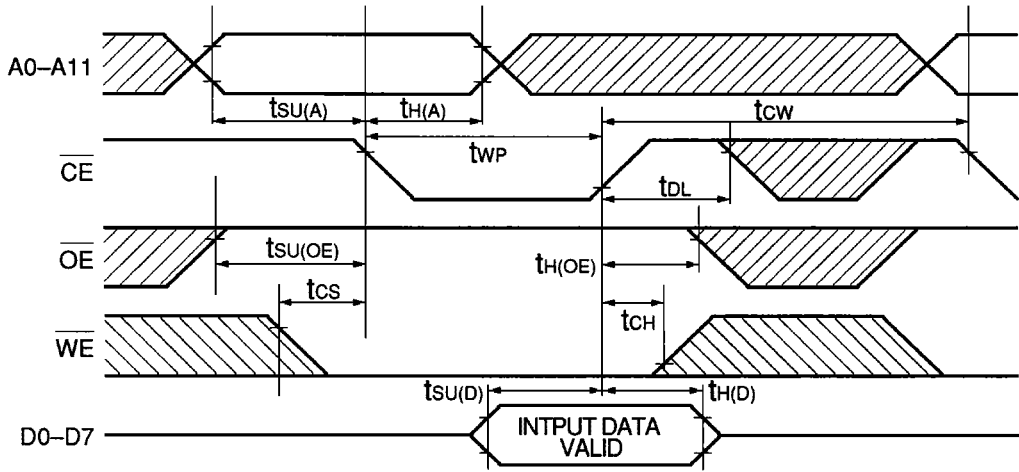
**READ TIMING OF ATTRIBUTE MEMORY**



**WRITE CYCLE OF ATTRIBUTE MEMORY ( $\overline{\text{CE}}$  CONTROLLED WRITE)  
(2K Bytes EEPROM ATTRIBUTE MEMORY)**

Symbol	Parameter	Min	Max	Unit
t <sub>cw</sub>	Write cycle time	15	—	ms
t <sub>wp</sub>	Write pulse width	150	—	ns
t <sub>su</sub> (A)	Address setup time	30	—	ns
t <sub>su</sub> (D)	Data setup time	80	—	ns
t <sub>h</sub> (D)	Data hold time	30	—	ns
t <sub>su</sub> (OE)	Output enable setup time	15	—	ns
t <sub>h</sub> (OE)	Output enable hold time	15	—	ns
t <sub>h</sub> (A)	Address hold time	100	—	ns
t <sub>cs</sub>	Write setup time	30	—	ns
t <sub>ch</sub>	Write hold time	0	—	ns
t <sub>dL</sub>	Data latch time	50	—	ns

**WRITE TIMING OF ATTRIBUTE MEMORY ( $\overline{WE}$  CONTROLLED WRITE)  
(2K Bytes EEPROM ATTRIBUTE MEMORY)**

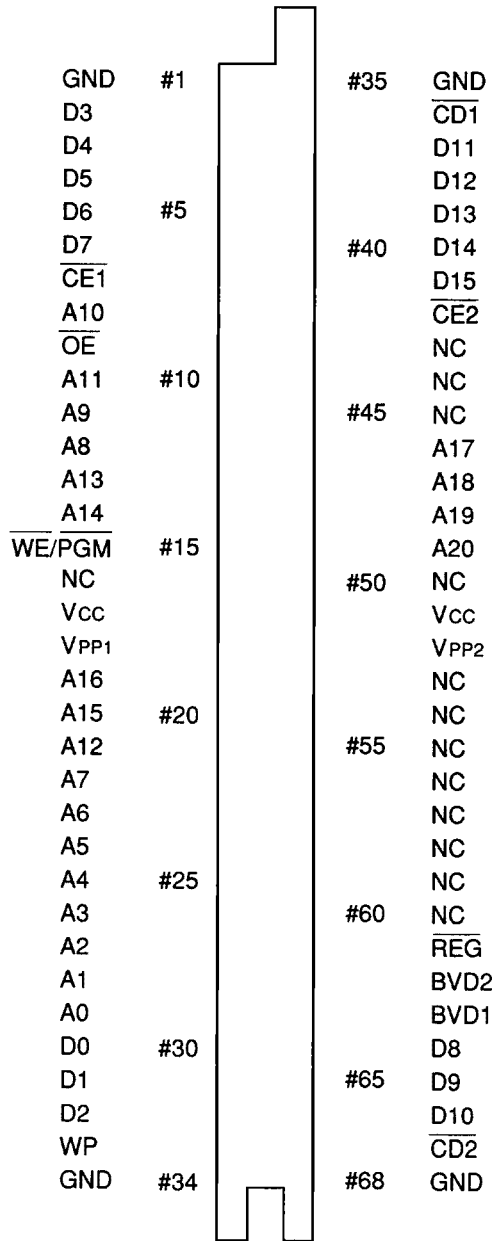


<< AC test conditions >>

Output load

: 1 TTL gate + 100 pF (include jig)

PIN ASSIGNMENT



## PIN ASSIGNMENT

Pin No.	Symbol	Pin No.	Symbol	Pin No.	Symbol
1	GND	23	A6	46	A17*
2	D3	24	A5	47	A18*
3	D4	25	A4	48	A19*
4	D5	26	A3	49	A20*
5	D6	27	A2	50	NC
6	D7	28	A1	51	VCC
7	$\overline{CE1}$	29	A0	52	VPP2
8	A10	30	D0	53	NC
9	$\overline{OE}$	31	D1	54	NC
10	A11	32	D2	55	NC
11	A9	33	WP**	56	NC
12	A8	34	GND	57	NC
13	A13	35	GND	58	NC
14	A14	36	$\overline{CD1}$	59	NC
15	WE/PGM	37	D11	60	NC
16	NC	38	D12	61	REG
17	VCC	39	D13	62	BVD2**
18	VPP1	40	D14	63	BVD1**
19	A16	41	D15	64	D8
20	A15	42	CE2	65	D9
21	A12	43	NC	66	D10
22	A7	44	NC	67	$\overline{CD2}$
		45	NC	68	GND

- Notes:
- \*A17 : BWB257, BWB513, BWB101, BWB201
  - \*A18 : BWB513, BWB101, BWB201
  - \*A19 : BWB101, BWB201
  - \*A20 : BWB201
  - NC : No connect
  - \*\*WP, BVD1, BVD2 : This line is connected to VCC inside Card.